

# Features

- Any frequency between 1 MHz and 220 MHz accurate to 6 decimal places
- LVPECL and LVDS output signaling types
- 0.6ps RMS phase jitter (random) over 12 kHz to 20 MHz bandwidth
- Frequency stability as low as ±5 ppm. Contact SiTime for tighter stability options
- Industrial and extended commercial temperature ranges
- Industry-standard packages: 3.2 x 2.5, 5.0 x 3.2 and 7.0 x 5.0 mm
- For frequencies higher than 220 MHz, refer to SiT5022 datasheet

## Applications

- SATA, SAS, 10GB Ethernet, Fibre Channel, PCI-Express
- Networking, broadband, instrumentation



Electrical Characteristics							
Parameter and Conditions	Symbol	Min.	Тур.	Max.	Unit	Condition	
	L	VPECL an	d LVDS, C	ommon E	lectrical C	haracteristics	
Supply Voltage	Vdd	2.97	3.3	3.63	V		
		2.25	2.5	2.75	V		
		2.25	-	3.63	V	Termination schemes in Figures 1 and 2 - XX ordering code	
Output Frequency Range	f	1	-	220	MHz		
Initial Tolerance	F_init	-2	-	2	ppm	At 25°C after two reflows	
Stability Over Temperature	F_stab					Over operating temperature range at rated nominal power	
		-5	-	+5	ppm	supply voltage and load.	
<b>A A A B</b>						Contact SiTime for tighter stability options.	
Supply Voltage	F_vdd	-	50	-	ppb	±10% Vdd	
Output Load	F_load	-2.5	0.1	-	ppm	15 pF ±10% of load 25°C	
First Year Aging	F_aging1		_	+2.5	ppm		
10-year Aging	F_aging10	-5 -40	_	+5 +85	°C	25°C Industrial	
Operating Temperature Range	T_use	-40	-	+05	°C	Extended Commercial	
Pull Range	PR			-	-		
Upper Control Voltage	VC_U	± Vdd-0.1	12.0, ±20, ±0		ppm V	All Vdds. Voltage at which maximum deviation is guaranteed.	
Control Voltage Range	VC_U VC L	-	_	0.1	V	All vuus. voltage at which maximum deviation is guaranteed.	
Control Voltage Input Impedance	Z vc	100		0.1	kΩ		
Frequency Change Polarity			Positive slope		-		
Control Voltage -3dB Bandwidth	V BW	-	-	8	kHz		
Input Voltage High	VIH	70%	_	_	Vdd	Pin 1, OE or ST	
Input Voltage Low	VIL	_	_	30%	Vdd	Pin 1, OE or ST	
Input Pull-up Impedance	Zin	_	100	250	kΩ	Pin 1, OE logic high or logic low, or ST logic high	
input i un-up impedance	۰۰۰ ۲_۰۰	2	-	200	MΩ	Pin 1, ST logic low	
Start un Tima	T atart	-	6	10		Measured from the time Vdd reaches its rated minimum value.	
Start-up Time	T_start		6	10	ms		
Resume Time	T_resume	-	0	-	ms	In Standby mode, measured from the time ST pin crosses	
Duty Cycle	DC	45		55	%	Contact SiTime for tighter duty cycle	
		L		and AC C			
Current Consumption	Idd	-	61	69	mA	Excluding Load Termination Current, Vdd = 3.3V or 2.5V	
OE Disable Supply Current	I_OE	-	-	35	mA	OE = Low OE = Low	
Output Disable Leakage Current	I_leak	-	_	1 100	μΑ		
Standby Current	I_std	-	_		μA	ST = Low, for all Vdds	
Maximum Output Current	I_driver VOH	- Vdd-1.1	-	30 Vdd-0.7	mA V	Maximum average current drawn from OUT+ or OUT- See Figure 1(a)	
Output High Voltage Output Low Voltage	VOH	Vdd-1.1 Vdd-1.9	_	Vdd-0.7 Vdd-1.5	V	See Figure 1(a)	
Output Differential Voltage Swing	VOL V Swing	1.2	- 1.6	2.0	V	See Figure 1(b)	
Rise/Fall Time	v_Swing Tr, Tf	-	300	2.0 500	v ps	20% to 80%, see Figure 1(a)	
OE Enable/Disable Time	T_oe	_		115	ps ns	$f = 212.5 \text{ MHz} - \text{For other frequencies}, T_oe = 100 \text{ ns} + 3 \text{ period}$	
RMS Period Jitter	_	_	1.2	1.7	-	f = 100  MHz, VDD = 3.3V or 2.5V	
	T_jitt		1.2	1.7	ps	f = 156.25 MHz, VDD = 3.3V or 2.5V	
		_	1.2	1.7	ps	f = 212.5 MHz, VDD = 3.3V or 2.5V	
RMS Phase Jitter (random)	T_phj	_	0.6	0.85	ps ps	f = 156.25 MHz, Integration bandwidth = 12 kHz to 20 MHz, all	
	נייץ_י	-	0.0	0.00	ha	Vdds	

# **Electrical Characteristics**



# Electrical Characteristics (continued)

Parameter and Conditions	Symbol	Min.	Тур.	Max.	Unit	Condition				
		I	LVDS, DC	and AC Cl	naracteris	tics				
Current Consumption	ldd	-	47	55	mA	Excluding Load Termination Current, Vdd = 3.3V or 2.5V				
OE Disable Supply Current	I_OE	-	-	35	mA	OE = Low				
Differential Output Voltage	VOD	250	350	450	mV	See Figure 2				
Output Disable Leakage Current	l_leak	-	-	1	μA	OE = Low				
Standby Current	I_std	-	-	100	μA	ST = Low, for all Vdds				
VOD Magnitude Change	ΔVOD	-	-	50	mV	See Figure 2				
Offset Voltage	VOS	1.125	1.2	1.375	V	See Figure 2				
VOS Magnitude Change	ΔVOS	-	-	50	mV	See Figure 2				
Rise/Fall Time	Tr, Tf	-	495	600	ps	20% to 80%, see Figure 2				
OE Enable/Disable Time	T_oe	-	-	115	ns	f = 212.5 MHz - For other frequencies, T_oe = 100ns + 3 period				
RMS Period Jitter	T_jitt	-	1.2	1.7	ps	f = 100 MHz, VDD = 3.3V or 2.5V				
		-	1.2	1.7	ps	f = 156.25 MHz, VDD = 3.3V or 2.5V				
		-	1.2	1.7	ps	f = 212.5 MHz, VDD = 3.3V or 2.5V				
RMS Phase Jitter (random)	T_phj	-	0.6	0.85	ps	f = 156.25 MHz, Integration bandwidth = 12 kHz to 20 MHz, all Vdds				

# **Pin Description**

Pin	Мар		Functionality	
		V Control	Voltage control	
1	VC/OE/ST	Output Enable	H or Open: specified frequency output L: output is high impedance	Top View
		Standby	H or Open: specified frequency output L: Device goes to sleep mode. Supply current reduces to I_std.	VC/OE/ST 1 6 VDD
2	NC	NA	No Connect; Leave it floating or connect to GND for better heat dissipation	NC 2 5 OUT-
3	GND	Power	VDD Power Supply Ground	NC 2 5 OUT-
4	OUT+	Output	Oscillator output	GND 3 4 OUT+
5	OUT-	Output	Complementary oscillator output	GND 3 4 OUT+
6	VDD	Power	Power supply voltage	

# **Absolute Maximum**

Attempted operation outside the absolute maximum ratings may cause permanent damage to the part. Actual performance of the IC is only guaranteed within the operational specifications, not at absolute maximum ratings.

Parameter	Min.	Max.	Unit
Storage Temperature	-65	150	°C
VDD	-0.5	4	V
Electrostatic Discharge (HBM)	-	2000	V
Soldering Temperature (follow standard Pb free soldering guidelines)	-	260	°C

# **Thermal Consideration**

Package	θJA, 4 Layer Board (°C/W)	θJC, Bottom (°C/W)
7050, 6-pin	142	27
5032, 6-pin	97	20
3225, 6-pin	109	20

# **Environmental Compliance**

Parameter	Condition/Test Method		
Mechanical Shock	MIL-STD-883F, Method 2002		
Mechanical Vibration	MIL-STD-883F, Method 2007		
Temperature Cycle	JESD22, Method A104		
Solderability	MIL-STD-883F, Method 2003		
Moisture Sensitivity Level	MSL1 @ 260°C		



# Waveform Diagrams

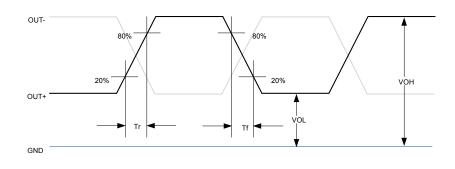


Figure 1(a). LVPECL Voltage Levels per Differential Pin (OUT+/OUT-)

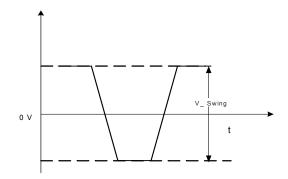


Figure 1(b). LVPECL Voltage Levels Across Differential Pair

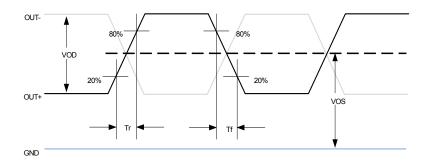


Figure 2. LVDS Voltage Levels per Differential Pin (OUT+/OUT-)



# **Termination Diagrams**

## LVPECL:

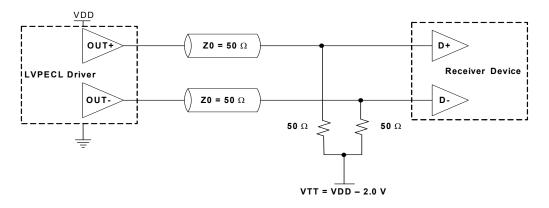


Figure 3. LVPECL Typical Termination

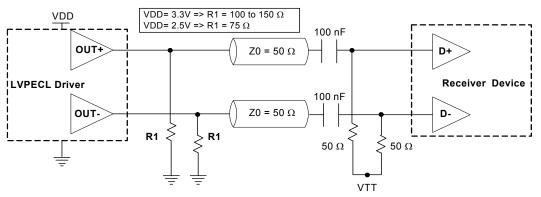


Figure 4. LVPECL AC Coupled Termination

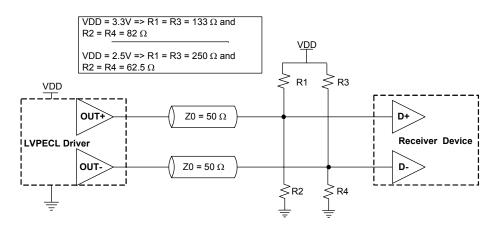


Figure 5. LVPECL with Thevenin Typical Termination



LVDS:

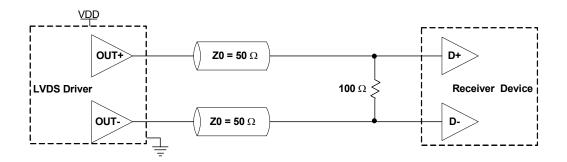
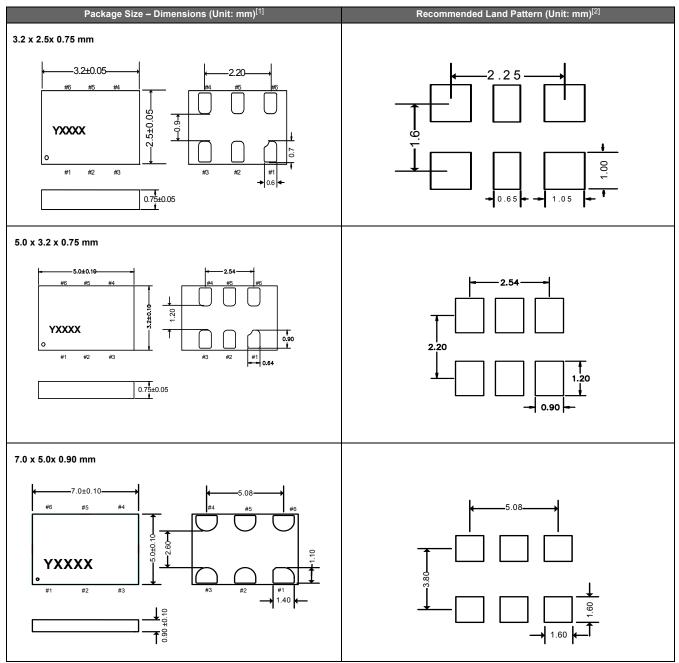


Figure 6. LVDS Single Termination (Load Terminated)



# **Dimensions and Patterns**



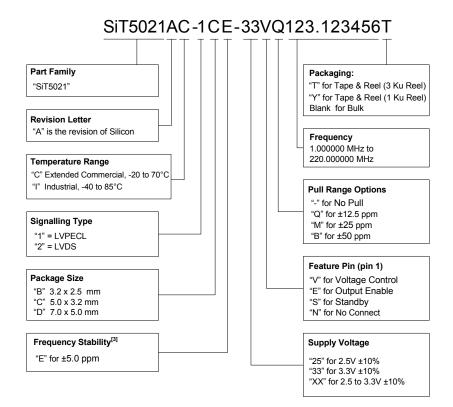
### Notes:

1. Top Marking: Y denotes manufacturing origin and XXXX denotes manufacturing lot number. The value of "Y" will depend on the assembly location of the device.

2. A capacitor of value 0.1  $\mu\text{F}$  between Vdd and GND is recommended.



# **Ordering Information**



### Note:

3. Contact SiTime for tighter stability options.

# **Ordering Codes for Supported Tape & Reel Packing Method**

Device Size	12 mm T&R (3ku)	12 mm T&R (1ku)	12 mm T&R (250u)	16 mm T&R (3ku)	16 mm T&R (1ku)	16 mm T&R (250u)
7.0 x 5.0 mm	-	-	-	Ţ	Y	Х
5.0 x 3.2 mm	Т	Y	Х	-	-	-
3.2 x 2.5 mm	Т	Y	Х	-	-	-

# **Frequencies Not Supported**

Range 1: From 209.000001 MHz to 210.999999 MHz



## **Revision History**

Version	Release Date	Change Summary
1.2	8/20/13	Original
1.3	12/16/13	Added input specifications, LVPECL/LVDS waveforms, packaging T&R options
1.4	12/11/14	Modified Thermal Consideration values and Pin Configuration table (pin 1) and drawing
1.5	11/12/15	<ul> <li>Revised stability over temperature and first year aging values in the electrical characteristics table</li> <li>Revised frequency stability and supply voltage options</li> </ul>

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# **Supplemental Information**

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# Silicon MEMS Outperforms Quartz

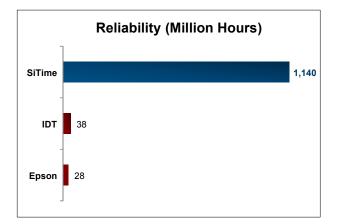


### **Best Reliability**

Silicon is inherently more reliable than quartz. Unlike quartz suppliers, SiTime has in-house MEMS and analog CMOS expertise, which allows SiTime to develop the most reliable products. Figure 1 shows a comparison with quartz technology.

### Why is SiTime Best in Class:

- SiTime's MEMS resonators are vacuum sealed using an advanced EpiSeal<sup>™</sup> process, which eliminates foreign particles and improves long term aging and reliability
- · World-class MEMS and CMOS design expertise





## Best Aging

Unlike quartz, MEMS oscillators have excellent long term aging performance which is why every new SiTime product specifies 10-year aging. A comparison is shown in Figure 2.

### Why is SiTime Best in Class:

- SiTime's MEMS resonators are vacuum sealed using an advanced EpiSeal process, which eliminates foreign particles and improves long term aging and reliability
- Inherently better immunity of electrostatically driven MEMS resonator

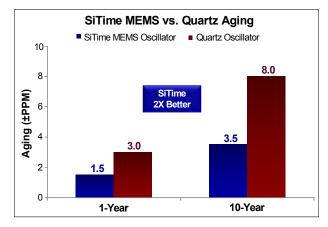


Figure 2. Aging Comparison<sup>[2]</sup>

## Best Electro Magnetic Susceptibility (EMS)

SiTime's oscillators in plastic packages are up to 54 times more immune to external electromagnetic fields than quartz oscillators as shown in Figure 3.

### Why is SiTime Best in Class:

- Internal differential architecture for best common mode noise rejection
- Electrostatically driven MEMS resonator is more immune to EMS

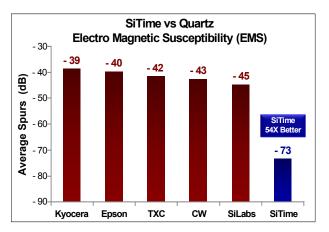


Figure 3. Electro Magnetic Susceptibility (EMS)<sup>[3]</sup>

## **Best Power Supply Noise Rejection**

SiTime's MEMS oscillators are more resilient against noise on the power supply. A comparison is shown in Figure 4.

### Why is SiTime Best in Class:

- On-chip regulators and internal differential architecture for common mode noise rejection
- · Best analog CMOS design expertise

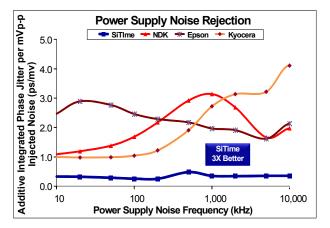


Figure 4. Power Supply Noise Rejection<sup>[4]</sup>



### **Best Vibration Robustness**

High-vibration environments are all around us. All electronics, from handheld devices to enterprise servers and storage systems are subject to vibration. Figure 5 shows a comparison of vibration robustness.

### Why is SiTime Best in Class:

- The moving mass of SiTime's MEMS resonators is up to 3000 times smaller than quartz
- Center-anchored MEMS resonator is the most robust design

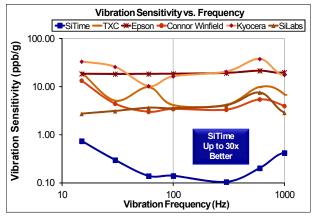


Figure 5. Vibration Robustness<sup>[5]</sup>

### Notes:

- 1. Data Source: Reliability documents of named companies.
- 2. Data source: SiTime and quartz oscillator devices datasheets.
- 3. Test conditions for Electro Magnetic Susceptibility (EMS):
  - According to IEC EN61000-4.3 (Electromagnetic compatibility standard)
     Field strength: 20/m
  - Field strength: 3V/m
  - Radiated signal modulation: AM 1 kHz at 80% depth
  - Carrier frequency scan: 80 MHz 1 GHz in 1% steps
  - Antenna polarization: Vertical
  - · DUT position: Center aligned to antenna

### Devices used in this test:

SiTime, SiT9120AC-1D2-33E156.250000 - MEMS based - 156.25 MHz Epson, EG-2102CA 156.2500M-PHPAL3 - SAW based - 156.25 MHz TXC, BB-156.250MBE-T - 3rd Overtone quartz based - 156.25 MHz Kyocera, KC7050T156.250P30E00 - SAW based - 156.25 MHz Connor Winfield (CW), P123-156.25M - 3rd overtone quartz based - 156.25 MHz SiLabs, Si590AB-BDG - 3rd overtone quartz based - 156.25 MHz

### 4. 50 mV pk-pk Sinusoidal voltage.

Devices used in this test:

SiTime, SiT8208AI-33-33E-25.000000, MEMS based - 25 MHz NDK, NZ2523SB-25.6M - quartz based - 25.6 MHz Kyocera, KC2016B25M0C1GE00 - quartz based - 25 MHz Epson, SG-310SCF-25M0-MB3 - guartz based - 25 MHz

- 5. Devices used in this test: same as EMS test stated in Note 3.
- 6. Test conditions for shock test:
- MIL-STD-883F Method 2002
- Condition A: half sine wave shock pulse, 500-g, 1ms
- Continuous frequency measurement in 100 µs gate time for 10 seconds
- Devices used in this test: same as EMS test stated in Note 3

7. Additional data, including setup and detailed results, is available upon request to qualified customers. Please contact productsupport@sitime.com.

# Best Shock Robustness

SiTime's oscillators can withstand at least 50,000 g shock. They all maintain their electrical performance in operation during shock events. A comparison with quartz devices is shown in Figure 6.

### Why is SiTime Best in Class:

- The moving mass of SiTime's MEMS resonators is up to 3000 times smaller than quartz
- Center-anchored MEMS resonator is the most robust design

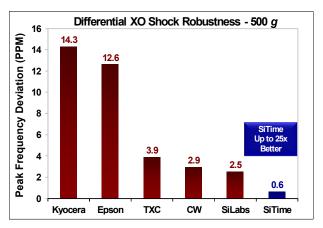


Figure 6. Shock Robustness<sup>[6]</sup>

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If "No," please sugge	If "No," please suggest improvements that we can make:						
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